Electron-ID BDT

0.94
0.96
0.98
1.00

13 TeV

CMS Simulation

Z → ee (simulation)

Z → ee (embedded)

All stat. uncertainties multiplied by 10

|η| < 0.8

N_{evts}

10^6
10^5
10^4
10^3
10^2
100

Electron-ID BDT